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09/724,197

Applicant(s)/Patent under Reexamination

GETTEMY ET AL.

Examiner

Jin-Cheng Wang

Art Unit 2628

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		Application/Control No.	Applicant(s)/	Applicant(s)/Patent under Reexamination	
ISS	Issue Classification		GETTEMY ET AL.	r AL.	
		Examiner	Art Unit		
		Wang, Jin-Cheng	2628		
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	ORIGINAL	INAL	INTERNATIONA	INTERNATIONAL CLASSIFICATION	
	CLASS	SUBCLASS	CLAIMED	NON-CLAIMED	
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(Date)

(Primary Examiner)

(Date)

(Legal Instruments Examiner)

Part of Paper No.

O.G. Print Figure Fig. 7

O.G. Print Claim(s) Claim 1

Total Claims Allowed: 21

KEE M. TUNG SUPERVISORY PATENT EXAMINER

Gintherynams (Assistant Examiner) U.S. Patent and Trademark Office